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PTC/SB/08A (07-05)
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

 Complete if Known

 Application Number
 10/669,141

 Filing Date
 09/23/2003

 First Named Inventor
 Milan R. Kokta

 Art Unit
 1775

 Examiner Name
 Stephen J. Stein

 Attorney Docket Number
 1075-B14282

	U. S. PATENT DOCUMENTS							
Examiner Initials*	Cite No.1	Document Number Number-Kind Code ^{2 (f known)}	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear			
535	Al	US- 3,753,775	08/21/1973	Robinson et al.				
S3 5	Bl	US- 3,964,942	06/22/1976	Berkenblit et al.				
535	Cl	US- 4,649,070	03/10/1987	Kondo et al.				
5755	DI	^{US-} 4,657,754	04/14/1987	Bauer et al.				
535	El	^{US-} 5,643,044	07/01/1997	Lund				
535	FI	US- 5,742,026	04/21/1998	Dickinson, Jr. et al.				
535	G1	US- 5,989,301	11/23/1999	Laconto, Sr. et al.				
555	HI	US- 6,048,577	04/11/2000	Garg				
535	I 1	US- 6,238,450 B1	05/29/2001	Garg et al.				
535	J1	US- 6,258,137 B1	07/10/2001	Garg et al.				
535	ΚI	^{US-} 6,265,089 B1	07/24/2001	Fatemi et al.				
575	LI	^{US-} 6,364,920 B1	04/02/2002	Garg et al.				
SSS	MI	^{US-} 6,391,072 B1	05/21/2002	Garg				
535	NI	us- 6,406,769 B1	06/18/2002	Delabre				
535	Οl	US- 6,418,921 B1	07/16/2002	Schmid et al.				
2,22	Pl	US- 2001/0026950 A1	10/04/2001	Sunakawa et al.				
535	Q1	US- 2002/0028314 A1	03/07/2002	Tischler et al.				
535	RI	US- 2002/0030194 A1	03/14/2002	Camras et al.	·			
550	SI	US- 2003/0190770 A I	10/09/2003	Yeom et al.				

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Examiner Initials*	Cite No.1		Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages	Γ			
		Country Code ⁸ "Number ⁴ "Kind Code ⁸ (if known)	MM-DD-YYYY		Or Relevant Figures Appear	To			
SSS	TI	CN 1291795	04/18/2001	Guanglei Sci & Tech Co. Ltd.	English Abstract Only				
535	UI	CN 1379484	11/13/2002	Univ Qinghua	English Abstract Only				
575	VI	CN 1469459	01/21/2004	Fudi Elect. Mat. Co. Ltd.	English Abstract Only				
535	WI	CN 1476046	02/18/2004	Shanghai Prec. Opt. Instr	English Abstract Only				
535	Χı	CN 1476047	02/18/2004	Shanghai Prec. Opt. Instr	English Abstract Only				
523	YI	EP 997445	05/03/2000	Corning Inc.	English Abstract Only				

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"EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if fot if conformance and not considered, include copy of this form with next communication to applicant. 'Applicant's unique citation designation number (optional). "See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. "Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). "For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document." Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. "Applicant is to place a check mark here if English language Translation is attached.

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Sheet 2

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(Use as many sheets as necessary)

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Application Number 10/669,141

Filing Date 09/23/2003

First Named Inventor Milan R. Kokta

Art Unit 1775

Examiner Name Stephen J. Stein

Attorney Docket Number 1075-B14282

			U. S. PATENT	DOCUMENTS	
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ^{2 (f known)}	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
5755	A2	US- 2003/0213950 A1	11/20/2003	Hwang	
SIS	B2	US- 2004/0063236 A1	04/01/2004	Kwak et al.	
277	C2	US- 2004/0089220 A1	05/13/2004	Kokta et al.	
227	D2	^{US-} 3,808,065	04/30/1974	Robinson et al.	
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225	F2	US- 4,347,210	08/31/1982	Maguire, et al.	
722	G2	US- 5,968,267	10/19/1999	Li	
222	H2	US- RE38,489 E	04/26/2004	Thony et al.	
5.22	12	US- 6,846,434 B1	01/25/2005	Akselrod	
	J2	US-			
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	N2	US-			
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	S2	US-			

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Examiner Initials*	Cite No.1	Cite Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages	Ι,		
	Country Code ⁸ "Number ⁴ "Kind Code ⁸ (if known)	MM-DD-YYYY		Or Relevant Figures Appear				
5,22	T2	EP 1298709	04/02/2003	NGK Insulators Ltd.	English Abstract Only	L		
535	U2	EP 1394867	03/03/2004	Samsung Elect. Co. Ltd.	English Abstract Only	L		
222	V2	JP 53-043481	04/19/1978	Matsushita Elec Ind. Co. Ltd.	English Abstract Only	L		
242	W2	JP 79-026873	09/06/1979	Nippon Elect. Co.	English Abstract Only	L		
535	X2	JP 58-090736	05/30/1983	Tokyo Shibaura Elect. Co	English Abstract Only	L		
225	Y2	JP 61-142759	06/30/1986	NGK Spark Plug Co. Ltd.	English Abstract Only	Γ		

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Complete if Known					
Application Number	10/669,141				
Filing Date	09/23/2003				
First Named Inventor	Milan R. Kokta				
Art Unit	1775				
Examiner Name	Stephen J. Stein				
Attorney Docket Number	1075-BI4282				

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	A3	Number-Kind Code ^{2 (# known)} US-	-		Figures Appear			
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		Country Code ³ "Number ⁴ "Kind Code ⁵ (if known)	MM-DD-YYYY		Or Relevant Figures Appear	T ⁶			
522	T3	JP 62-123059	06/04/1987	Narumi Seito KK	English Abstract Only				
555	U3	JP 7-235692	09/05/1995	Sony Corp.	English Abstract Only				
57 {	V3	JP 8-040797	02/13/1996	Kyocera Corp.	English Abstract Only	L			
222	W3	JP 8-083802	03/26/1996	Shingijutsu Kigyodan	English Abstract Only				
575	X3	JP 8-095233	04/12/1996	Tono Seiki YG	English Abstract Only				
550	Y3	JP 9-129651	05/16/1997	Hewlett-Packard Co.	English Abstract Only				

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Complete if Known					
Application Number	10/669,141				
Filing Date	09/23/2003				
First Named Inventor	Milan R. Kokta				
Art Unit	1775				
Examiner Name	Stephen J. Stein				
Attorney Docket Number	1075-BI4282				

U. S. PATENT DOCUMENTS							
Examiner Initials*	Cite No.1	Document Number Number-Kind Code ^{2 (# known)}	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
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Examiner Initials*	Cite No.1	Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages				
		Country Code ³ "Number ⁴ "Kind Code ⁵ (if known)	MM-DD-YYYY		Or Relevant Figures Appear				
575	T4	JP 9-129928	05/16/1997	Toshiba KK	English Abstract Only				
535	U4	JP 11-195813	07/21/1999	Toshiba Denshi Eng. KK	English Abstract Only				
555	V4	JP 11-235659	08/31/1999	Ricoh KK	English Abstract Only	E			
555	W4	JP 11-274559	10/08/1999	Sanyo Elect. Co. Ltd.	English Abstract Only				
555	X4	JP 2000-228367	08/15/2000	Samsung Elect. Co. Ltd.	English Abstract Only				
535	Y4	JP 2000-331940	11/30/2000	Sony Corp.	English Abstract Only	Г			

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Sheet 5

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Complete if Known				
Application Number	10/669,141			
Filing Date	09/23/2003			
First Named Inventor	Milan R. Kokta			
Art Unit	1775			
Examiner Name	Stephen J. Stein			
Attorney Docket Number	1075-B14282			

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Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear				
	A5	Number-Kind Code ^{2 (# known)} US-	- 		1,95,507,44,50				
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	FOREIGN PATENT DOCUMENTS							
Examiner Cite Initials* No.	Cite No.1		Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages			
		Country Code ^{3 -} Number ^{4 -} Kind Code ⁵ (if known)	MM-DD-YYYY			Or Relevant Figures Appear		
515	T5	JP 2001-010898	01/16/2001	NEC Corp.	English Abstract Only			
535	U5	JP 2001-198808	07/24/2001	Morioka Seiko Kogyo KK	English Abstract Only			
87 5	V5	JP 2001-220295	08/14/2001	Namiki Seimitsu Hoseki KK	English Abstract Only			
टउ	W5	JP 2001-253800	09/18/2001	Namiki Seimitsu Hoseki KK	English Abstract Only			
275	X5	JP 2002-012856	01/15/2002	Neos KK	English Abstract Only			
538	Y5	JP 2002-050577	02/15/2002	Namiki Seimitsu Hoseki KK	English Abstract Only			

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Sheet 6

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Application Number	10/669,141				
Filing Date	09/23/2003				
First Named Inventor	Milan R. Kokta				
Art Unit	1775				
Examiner Name	Stephen J. Stein				
Attorney Docket Number	1075-BI4282				

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		Country Code ⁸ "Number ⁴ "Kind Code ⁸ (if known)	MM-DD-YYYY I		Or Relevant Figures Appear	۲		
522	T6	JP 2002-158377	05/31/2002	Matsushita Denki Sangyo K.K.	English Abstract Only			
555	U6	JP 2002-255694	09/11/2002	Kyocera Corp.	English Abstract Only			
SIS	V6	JP 2002-353425	12/06/2002	Kyocera Corp.	English Abstract Only			
722	W6	JP 2003-045829	02/14/2003	Hitachi Chem Co. Ltd.	English Abstract Only			
225	X6	JP 2003-113000	04/18/2003	Hitachi Cable Ltd.	English Abstract Only			
512	Y6	JP 2003-124151	04/25/2003	Disco KK	English Abstract Only	Г		

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SIZ	T7	JP 2003-165042	06/10/2003	Okamoto Kosaku Kikai Scisakusho KK	English Abstract Only			
222	U7	JP 2003-273022	09/26/2003	Namiki Seimitsu Hoseki KK	English Abstract Only			
233	V7	JP 2003-320521	11/11/2003	Tokyo Tungsten KK	English Abstract Only			
STS	W7	JP 2003-334754	11/25/2003	Nippon Microcoating KK	English Abstract Only			
رتى	X7	JP 2003-338638	11/28/2003	Nichia Kagaku Kogyo KK	English Abstract Only			
120	Y 7	JP 2004-006867	01/08/2004	Matsushita Denki Sagyo KK	English Abstract Only			

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		FORE	IGN PATENT DOC	JMENTS		
Examiner Initials*	Cite No.	Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages	
		Country Code ³ "Number ⁴ "Kind Code ⁵ (if known)	MM-DD-YYYY		Or Relevant Figures Appear	T
ट्य	T8	JP 2004-014691	01/15/2004	Mitsubishi Gas Chem Co Inc.	English Abstract Only	
535	U8	JP 2004-140394	05/13/2004	Nissan Chem Ind. Ltd.	English Abstract Only	
535	V8	KR 2002-043128	06/08/2002	Ulsan College	English Abstract Only	L
535	W8	SU 1781271	12/15/1992	Krasy Poly (Kypo)	English Abstract Only	Ĺ
225	X8	TW 550836	09/01/2003	Ind. Tech. Res. Inst.	English Abstract Only	
522	Y8	WO 2000/68332	11/16/2000	MPM Ltd.	English Abstract Only	Г

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Sheet 9

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Complete if Known					
Application Number	10/669,141				
Filing Date	09/23/2003				
First Named Inventor	Milan R. Kokta				
Art Unit	1775				
Examiner Name	Stephen J. Stein				
Attorney Docket Number	1075-R14282				

			U. S. PATENT D	OCUMENTS	
Examiner Initials*	Cite No.1	Document Number Number-Kind Code ^{2 (f known)}	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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Exeminer Initials*	Cite No.1	Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages	
		Country Code ³ "Number ⁴ "Kind Code ⁵ (if known)	MM-DD-YYYY		Or Relevant Figures Appear	Te
SJS	T9	WO 2002/92674	11/21/2002	US Sec of Navy	English Abstract Only	
222	U9	WO 2004/33769	04/22/2004	Unisearch Ltd.	English Abstract Only	
	V9	·			English Abstract Only	
	W9				English Abstract Only	
	X9				English Abstract Only	
	Y9				English Abstract Only	

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Complete If Known m 1449/PTO **Application Number** 10/669,141 INFORMATION DISCLOSURE **Filing Date** 09/23/2003 STATEMENT BY APPLICANT **First Named Inventor** Milan R. Kokta **Art Unit** 1775 (Use as many sheets as necessary) **Examiner Name** Stephen J. Stein Sheet **Attorney Docket Number** 10 of 13 1075-BI4282

		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
222	A10	Aeschlimann, R. et al., "The Chemical Polishing of Magnesium Aluminate Spinel in Pyrophosphoric Acid", MAT. RES. BULL., Vol. 5, pgs 167-172, 1970.	
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535	D10	Kurobe, Toshiji, et al., "Magnetic Field-Assisted Lapping", BULL. JAPAN SOC. OF PREC. ENGG., Vol. 20, No. 1, March 1986, pgs 49-51.	
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555	G10	Richter, F., et al., "Herstellung und Aurichtung Von MgAl-Spinell-Substraten für die Halbleiterepitaxie", KRISTALL UND TECHNIK, Vol. 10, No. 3, 1975, pgs 33-348.	
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Examiner		Date	1
Signature	Sten Sten	Considered	1/7/2006

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INFO	ORMATION	l DIS	CLOSURE	Filing Date	09/23/2003
STA	TEMENT E	BY A	PPLICANT	First Named Inventor	Milan R. Kokta
	//les es many sh			Art Unit	1775
	(Use as many sh	eus as n	ecessary)	Examiner Name	Stephen J. Stein
Sheet	11	of	13	Attorney Docket Number	1075-BI4282

		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
535	A11	Yanina, S., et al., "Moving Steps and Crystal Defects on Spinel Surfaces", MAT. RES. SOC. SYMP., Vol. 620, 2000, pgs M9.4.1-M9.4.6.	
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575	DH	Sung, Y., et al., "High Rate Etching of Sapphire Wafer Using Cl2BCl3Ar Inductively Coupled Plasmas", MAT. SCI. & ENG.: SOLD STATE MAT, Vol. B82, No. 1-3 2000, pgs 50-52. (ABSTRACT ONLY)	
5 3 5	E11	Wang, X., et al., "Chemical Polishing of Sapphire for Growth of GaN", CHINESE JOURNAL OF SEMICONDUCTORS, Vol. 18, No. 11, pgs 867-871, 1997. (ABSTRACT ONLY)	
SZS	F11	Lee, J., et al., "Scribing and Cutting a Blue LED Wafer Using a Q-Switched Nd:YAG Laser", APPLIED PHYSICS, Vol. 70, No. 5, pgs 561-564, 2000. (ABSTRACT ONLY)	
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1000				Application Number	10/669,141	
INFO	RMATION	DIS	CLOSURE	Filing Date	09/23/2003	
STA	STATEMENT BY APPLICANT			First Named Inventor	Milan R. Kokta	
	##			Art Unit	1775	
(Use as many sheets as necessary)				Examiner Name	Stephen J. Stein	
Sheet	12	of	13	Attorney Docket Number	1075-B14282	

		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
228	A12	Jeong, C., et al., "Dry Etching of Sapphuire Substrate for Device Separation in Chlorine-Based Inductively Coupled Plasmas", MAT. SCI. & ENG.: SOLID STATE MATERIALS, Vol. 93, No. 1-3, pgs 60-63, 2002. (ABSTRACT ONLY)	
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<i>23</i> 5	E12	Blecha, Z., et al., "On Fabrication of Sapphire Substrates (1102) for Epitaxy of Monocrystalline Silicon", JEMNA MECHANIKA A OPTIKA, Vol., 28, No. 12, pgs 249-351, 1983. (ABSTRACT ONLY)	
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575	G12	Ehman, M., et al., "Mechanical Preparation of Sapphire Single-Crystal Surfaces by Vibratory Techniques", METALLOGRAPHY, Vol. 9, No. 4, pgs 333-339, 1976. (ABSTRACT ONLY)	
535	H12	Druminiski, M., et al., "Deposition of Epitaxial Films on Spinel and Sapphire. Influence of Substrate Preparation", SIEMENS FORSCHUNGS - UND ENTWICKLUNGSBERICHTE, Vol. 5, No. 3, pgs 139-145, 1976. (ABSTRACT ONLY)	
222	I12	Cullen, G., "The Preparation and Properties of Chemically Vapor Deposited Silicon on Sapphire and Spinel", JOURNAL OF CRYSTAL GROWTH, Vol. 9, pgs 107-125, 1971. (ABSTRACT ONLY)	
ر وی	J12	Liu, L., et al., "Substrates for Gallium Nitride Epitaxy", MAT. SCI. & ENG. REPORTS, Vol. R37, No. 3, pgs 61-127, 2000. (ABSTRACT ONLY)	

Examiner Date Signature Considered

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rork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number. Complete if Known 600m 1449/PTO **Application Number** 10/669,141 **Filing Date** INFORMATION DISCLOSURE 09/23/2003 STATEMENT BY APPLICANT **First Named Inventor** Milan R. Kokta Art Unit 1775 (Use as many sheets as necessary) **Examiner Name** Stephen J. Stein **Attorney Docket Number** Sheet 13 of 13 1075-BI4282

		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
225	A13	Khattak, C., et al., "Production of Sapphire Blanks and Substrates for Blue LEDs and LDs", MAT. RES. SOC. SYMP PROCEEDINGS, V. 743, pgs 219-224, 2002. (ABSTRACT ONLY)	
S3J	B13	Gutsche, H., et al., "Polishing of Sapphire with Colloidal Silica", JOURNAL OF THE ELECTROCHEMICAL SOCIETY, Vol. 125, No. 1, 1978, pgs 136-138, 1978. (ABSTRACT ONLY)	
222	C13	Duffy, M., et al., "Semiconductor Measurement Technology: Method to Determine the Quality of Sapphire, (NOTE) Final Report", RCA Labs, 1980, 77 pgs. (ABSTRACT ONLY)	
222	D13	Duffy, M., et al, "Method to Determine Qulity of Sapphire, (NOTE) Interim Rept.", RCA Labs, 1975, 88 pgs. (ABSTRACT ONLY)	
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SIS	F13	Edgar, J., et al., "Substrates for Gallium Nitride Epitaxy", MAT. SCI. & ENG., PART R, Vol. R37, No. 3, pgs 61-127, 2002. (ABSTRACT ONLY)	
222	G13	Author Unkown, "Specifications for Polished Monocrystalline Sapphire Substrates" 1996, Affiliation (Issuing Organization) SEMI Semiconductor Equipment & Materials International, USA. (Bibliographic Entry Only).	
525	H13	Search Report for Technical Articles (Including various Abstracts of certain Identified References)	
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